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## **IEEE RAMS 2015 Program**

## "Rci g 001P - Poster Session 1

The Reliability, Availability, and Maintainability of Ground Systems in Support of Space Missions - 01P1 - 31

Jya-Syin Chien, The Aerospace Corporation (United States); Roland Duphily, The Aerospace Corporation (United States); Yum-Tong Lee, The Aerospace Corporation (United States)

Asset Maintenance Optimization: Case-Study of an Offshore Wind Farm - 01P2 - 35 *Yizhak Bot*, *BQR* (*Israel*)

How the Internet of Things Will Improve Reliability Tracking - 01P3 - 67 *Karen Bowman*, *PTC* (United States); Brad Cline, PTC (United States)

Software Contributions to the Reliability of Systems of Systems - 01P4 - 70 *Taz Daughtrey*, *Cyber Security Information Analysis Center (United States)* 

14 Ways to Learn Reliability Engineering - 01P5 - 76 *Fred Schenkelberg*, *FMS Reliability (United States)* 

Modelling Delay Propagation within Train Communication Network - 01P7 - 101 Xin Jiang, Beihang University (China); Linhan Guo, Beihang University (China); Sheng Hong, Beihang University (China); Jian Zhou, Beihang University (China)

Reliability Growth Assessment under Operating Stress Conditions - 01P8 - 102 Khanh Le Son, Institut des Sciences et Techniques de l'Ingénieur d'Angers (France); Laurent Saintis, LARIS - ISTIA - Université d'Angers (France); Tristan Le Fevre, SNECMA (France); Michal Kurela, CNES (France)

Organic Embedded Architecture for Sustainable FPGA SoftCore Processors - 01P9 - 111 Navid Khoshavi, University of Central Florida (United States); Ronald F. DeMara, University of Central Florida (United States); Kening Zhang, Baidu Inc. (China); Jaafar Alghazo, Prince Mohammad Bin Fahd University (United States)

The Reliability Sensitivity Analysis Based on System Failure Evolution - 01P11 - 137 *Qingli Wang*, Xi'an Jiaotong University (China); Jianmin Gao, (China); Kun Chen, (China); Xu Gao, (China)

A SOS Reliability Evaluate Approach Based on GERT - 01P12 - 144 **Tianjian Wen**, Beihang University (China); Xing Pan, Beihang University (China); Congjiao He, Beihang University (China)

Reliability modeling of complex mechanism system using GBN - 01P13 - 148 pidong wang, Science and Technology on Reliability and Environment Engineering Laboratory (China); Jianguo Zhang, Science and Technology on Reliability and Environment Engineering

Laboratory (China); Linjie Kan, Science and Technology on Reliability and Environment Engineering Laboratory (China); Lechang Yang, Science and Technology on Reliability and Environment Engineering Laboratory (China)

Importance Measure of Multi-state Element Variation Based on F-VMEA - 01P14 - 149 Min Luo, IEEE reliability society (China); Shengkui Zeng, Beihang University (China); Jianbin Guo, (China); Huan Tang, Beihang University (China)

Physics of Failure, Predictive Modeling & Data Analytics for LOCA Frequency - 01P16 - 221 *Nicholas O'Shea*, University of Illinois at Urbana-Champaign (United States); Justin Pence, NPRE at UIUC, Argonne National Lab (United States); Zahra Mohaghegh, Department of Nuclear, Plasma, and Radiological Engineering, University of Illinois at Urbana-Champaign (United States); Ernie Kee, YK.risk, LLC (United States)

FMECA Applications and Lessons Learnt - 01P18 - 254 Ebru nihal Cetin, TAI - Turkish Aerospace Industries (Turkey)

Reliability Survey of Military Acquisition Systems - 01P19 - 262

Jonathan Bell, Institute for Defense Analyses (United States); Matthew Avery, (United States);

Michael Wells, (United States)

Reliability Analysis of Organic Fibres based on Small Data Volumes. - 01P20 - 274

Marcin Hinz, University of Wuppertal (Germany); Andreas Luecker, University of Wuppertal (Germany); Georg Knübel, Henkel AG & Co KGaA (Germany); Stefan Bracke, University of Wuppertal Chair of Safety Engineering and Risk Management (Germany)

Reliability Prediction Method with Field Environment Variation - 01P21 - 296 Wei Dai, Beihang University (China); Yikun Cai, (China); MA Xiaobing, Beihang University (China); ZHAO Yu, Beihang University (China)

#### 002P - Poster Session 2

An Improved Method for Mission Risk Analysis of the Satellite ACS - 01P6 - 81 **Xiaopeng Li**, (China); Li Fuqiu, (China); Liming Ren, China Academy of Aerospace Standardization and Product Assurance (China); Ming Zuo, University of Alberta (Canada)

Research on the Wear Mechanism Coupling Modeling of Spool Valve - 02P1 - 36 Yunxia Chen, Beihang University (China); **Hailong Jing**, Beihang University (China); Xun Liao, (China); Rui Kang, Beihang University (United States)

Correlated Consecutive k-out-of-n Failed Systems - 02P2 - 75

Bentolhoda Jafary, University of Massachusetts (United States); Lance Fiondella, University of Massachusetts (United States)

How to Improve your Ability to Persuade - 02P3 - 79 *Fred Schenkelberg*, FMS Reliability (United States)

CPI Evaluation for ULK Wafer in Foundry BEOL and Assembly Wafer Saw - 02P4 - 124 Morn Jin, Semiconductor Manufacturing International (Shanghai) Corp. (China); Wenwen He, Semiconductor Manufacturing International (Shanghai) Corp. (China); Kelly Yang, Semiconductor Manufacturing International (Shanghai) Corp. (China); Wei-Ting Chien, SMIC, Shanghai, China (China)

Maximizing the Lifetime of Heterogeneous Wireless Sensor Networks - 02P5 - 130 *Xiaoxi Liu*, *Beihang University (China); Ruiying Li*, *Beihang University, University of Arizona (China); Haitao Liao, University of Arizona (United States)* 

A Novel Performability Assessment Approach of Mobile Ad Hoc Network - 02P6 - 132 *Xiaolei Sun*, *Beihang University (China); Ning Huang, (China); Jian Zhou, Beihang University (China)* 

A Failure-mechanism-and-data Integrated System Degradation Analysis - 02P7 - 138 **Zhipeng Hao**, IEEE Reliability Society (China); Shengkui Zeng, Beihang University (China); Jianbin Guo, (China)

A New Hybrid Traffic Generation Model for TI Reliability Test - 02P8 - 159 *Weiqiang Wu*, *Beihang University (China); Ning Huang, (China); Yue Zhang, Beihang University (China)* 

Redundancy Allocation with Non-identical Component and Uncertainty - 02P9 - 160 Jianyu Zhao, IEEE reliability society (China); Shengkui Zeng, Beihang University (China); Jianbin Guo, (China); Chunbo Yang, IEEE reliability society (China)

Reliability Based Optimization in Hybrid Wireless Sensor Networks - 02P10 - 167

Amir Zonouz, University of Massachusetts, Dartmouth (United States); Liudong Xing, UMass Dartmouth (United States); Vinod Vokkarane, UMass Lowell (United States); Yan Sun, University of Rhode Island (United States)

IEEE 1633 – Standard for Recommended Practice on Software Reliability - 02P11 - 273 Ann Marie Neufelder, SoftRel, LLC (United States); Lance Fiondella, University of Massachusetts (United States); Louis Gullo, Raytheon (United States); Taz Daughtrey, Cyber Security Information Analysis Center (United States)

# 01C - Software Reliability Techniques and Applications

Early Modeling of Software Reliability Growth and Its Projected Reliab - 01C1 - 114 *Milena Krasich*, *Raytheon (United States)* 

Reliability Vibration Tests in Automotive - 01C2 - 9

David Delaux, VALEO (France); Marco Bonato, VALEO (France)

Innovative Methodology for Reliability Evaluations of Software Systems - 01C3 - 52 *Megan Jais*, U.S. Army Test and Evaluation Command (United States)

An Adaptive EM Algorithm for NHPP Software Reliability Models - 01C4 - 37 *Vidhyashree Nagaraju*, *University of Massachusetts (United States); Lance Fiondella, University of Massachusetts (United States)* 

## 01D - System Reliability Models

Reliability Analysis of Multi-state Systems with S-dependent Component - 01D1 - 65 Cuong Dao, University of Alberta (Canada); Ming Zuo, University of Alberta (Canada)

System Reliability Assessment Incorporating Interface Failure - 01D2 - 87 **Zhaojun Li**, Western New England University (United States); Mohammadsadegh Mobin, Western New England University (United States)

Reliability analysis of cold standby systems with scheduled backups - 01D3 - 21 *Qingqing Zhai*, Beihang University (China); Liudong Xing, UMass Dartmouth (United States); Rui Peng, University of Science & technology Beijing (China); Jun Yang, Beihang University (China)

Modeling and Analysis of Dependable Systems through GCTBN Models - 01D4 - 24 *Luigi Portinale*, *University of Piemonte Orientale (Italy)*; *Daniele Codetta-Raiteri*, *University of Piemonte Orientale (Italy)* 

# 02C - Physical Failure Modeling and Applications I

Reliability Test, Characterization and Modeling of Solid State Storage - 02C1 - 47 Jay Sarkar, HGST, Western Digital Corporation (United States); Feng-Bin Sun, HGST, A Western Digital Company (United States)

Investigation of BEOL Plasma Process Induced Damage on Gate Oxide - 02C2 - 57

Lingxiao Cheng, SMIC (China); ChiHsi Wu, (China - Taipei); JungChe Chang, SMIC (China - Taipei); Xiaofeng Xu, (United States)

Physics Based Reliability: A Method to Meet Life Cycle Affordability G - 02C3 - 28 Patrick Malone, MCR, LLC (United States); **Tuan Nguyen**, General Atomics Aeronautical (United States)

The Degradation Model of Servo Valve with Coupled Failure Mechanisms - 02C4 - 142 *Chunbo Yang*, *IEEE reliability society (China); Shengkui Zeng, Beihang University (China); Jianbin Guo, (China); Jianyu Zhao, IEEE reliability society (China)* 

#### 02D - Techniques for Repairable Systems Management

Geometric Renewal Process as Repairable System Model - 02D1 - 61

Vasiliy Krivtsov, Ford Motor Company (United States); Mark Kaminskiy, NASA Goddard Space Flight Center (United States)

Complexities of Systems Operational Availability Modeling - 02D2 - 198 **Dennis Anderson**, Sandia National Laboratories (United States); Charles Carter, Sandia

National Laboratories (United States); Tamara Brown, Sandia National Laboratories (United States)

On the Use of Jump-Diffusion Process for Maintenance Decision-Making - 02D3 - 169 Houda Ghamlouch, Institut Charles Delaunay, Université de Technologie de Troyes (France); Mitra Fouladirad, University of technology of Troyes (France); Antoine Grall, Université de Technologie de Troyes & CNRS UMR SMTR (France)

Repairable Item Inventory Model Optimization with Uncertainty Theory - 02D4 - 93

Meilin Wen, Beihang University (China); Qiao Han, Science and Technology on Reliability and

Environmental Engineering Laboratory, School of Reliability and Systems Engineering, Beihang

University (China)

## 02E - Maintenance Planning

Extraction and Exploitation of R&M Knowledge from a Fleet Perspective - 02E1 - 126 Simone Turrin, ABB, Corporate Research (Germany); Subanatarajan Subbiah, ABB Corporate Research (Germany)

Reliability Centered Maintenance Cost Modeling: Lost Opportunity Cost - 02E2 - 19 *Daniel Sillivant*, *University of Alabama in Huntsville (United States)* 

When will Spares Run Out? - 02E3 - 71

Mark Monaghan, Raytheon Corporation (United States)

Modeling Multiple Preventative Maintenance Actions in a RAMS Analysis - 14C3 - 40 *Jack Olivieri*, *MITRE Corporation (United States)* 

#### 03D - Prognostics and Health Management I

Multi-Branch Hidden Semi-Markov Modeling for RUL prognosis - 03D1 - 244 **Thanh Trung LE**, GIPSA-lab, Univ. Grenoble Alpes & CNRS (France); Christophe Berenguer, GIPSA Lab - Univ. Grenoble Alpes & CNRS (France); Florent CHATELAIN, GIPSA laboratory (France)

System Engineering Approach for Diagnostics of Electromechanical Systems - 03D2 - 214 *Paul Dumont*, *University of Southern California (United States)* 

Operation and Maintenance Decision Making using Prognostic Information - 03D3 - 105 **Seyed Niknam**, Western New England University (United States); John Kobza, University of Tennessee - Knoxville (United States); J. Wesley Hines, (United States)

Health-assessment Methodology Research for SMPS based on Simulation - 03D4 - 236 xuerong ye, (China); Cen Chen, Harbin Institute of Technology (China); Yixing Wang, Harbin Institute of Technology (China); Yuege Zhou, (China); George Vachtsevanos, Georgia Institute of Technology (United States)

#### 03E - R&M Applications in Safety Critical Systems

Reliability and Probabilistic Risk Assessment - How They Play Together - 03E1 - 10 Fayssal Safie, NASA (United States); Riichard Stutts, NASA (United States); Zhaofeng Huang, Aerojet Rocketdyne (United States)

Gas Turbine APU Reliability Modeling and Failure Forecasting - 03E3 - 210 **Peng Wang**, Pratt & Whitney AeroPower (United States); Shaonian Wang, China Southern Airlines (China); Lulu Wang, China Southern Airlines (China)

Replacement Interval Optimization for Aircraft Maintenance - 03E4 - 307 **Zigmund Bluvband**, ALD Ltd. (Israel); Sergey Porotsky, ALD Ltd. (Israel); Yang Lin, Shanghai Aircraft Design & Research Institute (SADRI) (China)

## **05C - Accelerated Life Testing Models**

Usage Based Predictive Transistor Aging Model to Optimize Test Limits on IO Circuits - 05C1 - 206

James Mendes, Intel (United States); Abishai Daniel, (United States)

An Updated Bibliography of Accelerated Test Plans - 05C2 - 17 *Wayne Nelson*, *Wayne Nelson Statistical Consulting (United States)* 

Accelerated Destructive Degradation Test with Initiation Time - 05C3 - 120 Haitao Liao, University of Arizona (United States); Ye Zhang, University of Arizona (United States); Yili Hong, Virginia Tech (United States)

Impact Analysis of Prior Distributions on ADT Bayesian Optimization Design Based on DIC - 05C4 - 145

**Tianji Zou**, School of Reliability and Systems Engineering, Beihang University (China); Xiaoyang Li, (China); Li Meijun, (China)

#### 05D - Applied R&M Management for Industry Solutions

Function Based Reliability Targets Under Budgetary Constraints - 05D1 - 253

Michael Bartholdt, University of Stuttgart, Institute of Machine Components (Germany); Bernd
Bertsche, University of Stuttgart, Institute of Machine Components (Germany)

Implementing a more-relevant Reliability Estimation Process - 05D2 - 26 *Les Warrington*, *Ops A La Carte (United States)* 

Reliability & Maintainability Applications in Logistics & Supply Chain - 05D3 - 183 *Amanda Gillespie*, SAIC (United States)

On Optimal Inspection Interval for Minimizing Maintenance Cost - 05D4 - 42 Huairui Guo, ReliaSoft (United States); Ferenc Szidarovszky, ReliaSoft (United States); Athanasios Gerokostopoulos, ReliaSoft Corporation (United States); Pengying Niu, ReliaSoft (United States)

## 05E - R & M Management Under New Challenges I

A Study of the Quantitative Methods that Support Reliability Centered Maintanance (RCM) Operation - 05E1 - 41

Angelica Alebrant Mendes, Universidade Federal do Rio Grande do Sul (Brazil); Jose Luis Duarte Ribeiro, (Brazil)

Early Detection for Quality & Reliability Management - 05E2 - 89 Wei-Ting Chien, SMIC, Shanghai, China (China); Ming Li, SMIC Corp Q&R, Shanghai, China (China); Mark Zhang, SMIC Corp Q&R, Shanghai, China (China)

Susceptibility of Spacecraft to Impact-Induced Electromagnetic Pulses - 05E4 - 204 Alexander Fletcher, Stanford University (United States); Donovan Mathias, (United States); Sigrid Close, Stanford University (United States)

System Availability Analysis under Redundancy Sharing of Standby Components - 14D1 - 119 **Tongdan Jin**, Texas State University (United States); Haitao Liao, University of Arizona (United States); Wei Xie, University of Arizona (United States); Wilkistar Otieno, University of Wisconsin-Milwaukee (United States)

## 06D - Optimizing R&M Cost and Performance

Optimal Sustainable Vehicle Replacement Model - 06D1 - 185 **Sharareh Taghipour**, Ryerson University (Canada); Nooshin Salari, Ryerson University (Canada)

Impact of System Redundancies on Optimization of the Support Solution - 06D2 - 272 *Tomas Eriksson*, *Systecon AB (Sweden)* 

Optimal Partly Repairable Spare Inventory Policy by MDP under Warranty - 06D3 - 217 *jiujiu Fan*, Beihang University (China); Linhan Guo, Beihang University (China); Wang Naichao, (China); Yi Yang, (China)

Estimating and Using Direct Operating Cost as a Design Parameter - 06D4 - 69 *Mike Neus*, *Bell Helicopter (United States); Collin Zreet, Bell Helicopter (United States); Zhuoqi Chen, (United States)* 

#### 06E - Reliability Testing

Optimizing Reliability Testing with Limited Resources - 06E1 - 190 *Amanda Gillespie*, *SAIC (United States)* 

Life Test Design Leveraging Prior Knowledge - 06E2 - 199

Jiliang Zhang, Tesla Motors (United States); Celine Geiger, Tesla Motors (United States)

Reliability Demonstration Testing: Can We Afford 80% Confidence? - 06E3 - 176

Darryl Kellner, Acquisition Logistics Engineering (United States); Steve Rogers, Acquisition Logistics Engineering (United States)

Bayesian Reliability Modeling for Pass/Fail Systems with Sparse Data - 06E4 - 83 **Zhaojun Li**, Western New England University (United States); Allan Mense, Raytheon (United States)

## 07C - Advances in Life Data Analysis

A System for Design Decisions Based on Reliability Block Diagrams - 07C1 - 179 **Pankaj Shrivastava**, Halliburton (United States); Bob Gissler, Halliburton (United States)

Tool Replacement Based On Pattern Recognition with LAD - 07C2 - 62 Yasser Shaban, École Polytechnique of Montreal (Canada); Soumaya Yacout, École Polytechnique of Montreal (Canada); Marek Balazinski, École Polytechnique of Montreal (Canada)

Nonparametric Data Reduction Approach for Large-Scale Survival Data Analysis - 07C3 - 232 *Keivan Sadeghzadeh*, *Northeastern University (United States); Nasser Fard, Northeastern University (United States)* 

Life Data Analysis using Competing Failure Modes Technique - 07C4 - 266 *Julio Pulido*, *ReliaSoft Corporation (United States)* 

## 07D - R&M Applications in Aerospace

A Crack Monitoring Method Based on Microstrip Patch Antenna - 07D1 - 95 Mabao Liu, School of Aerospace, Xi'an Jiaotong University (China); **Binbin Li**, Xi'an Jiaotong University (China); Hao Li, School of Aerospace, Xi'an Jiaotong University (China)

Strain Measurement based on Microstrip Patch Antennas - 07D2 - 96

Wenjuan Wang, School of Aerospace, Xi'an Jiaotong University (China); Teng Liu, School of Aerospace, Xi'an Jiaotong University (China); Hangyu Ge, School of Aerospace, Xi'an Jiaotong University (China); Mabao Liu, School of Aerospace, Xi'an Jiaotong University (China)

A Power Loss Model for a Solar String with Mixed Cell Types - 07D3 - 265 Wei Huang, Space Systems/Loral, LLC (United States); James Loman, Space Systems/Loral, LLC (United States); Anne Bieniek, Space Systems/Loral, LLC (United States); Frank Pelkofer, Space Systems/Loral, LLC (United States)

Battery Prognostics with Uncertainty Fusion for Aerospace Applications - 07D4 - 127 **Datong Liu**, Harbin Institute of Technology (China); Wei Xie, The University of Arizona (United States); Yu Peng, Harbin Institute of Technology (China); Siyuan Lu, Harbin Institute of Technology (China)

#### 07E - Reliability Modeling Techniques I

CCF Structural Reliability Estimation under Statistical Uncertainty - 07E1 - 58 *Ruoxing Gu*, China Academy of Engineering Physics (China); Jin Qin, (China)

Measuring Reliability under Aleatory and Epistemic Uncertainty - 07E2 - 115 **Zhiguo Zeng**, Beihang University (China); Rui Kang, Beihang University (United States); Meilin Wen, Beihang University (China); Yunxia Chen, Beihang University (China)

Mission Reliability Analysis of Phased-Mission Systems-of-Systems with Data Sharing Capability - 07E3 - 171

**Behrokh Mokhtarpour**, Southern Methodist University (United States); Jerrell Stracener, Southern Methodist University (United States)

Optimal Availability Improvement for Digital Switching Systems - 07E4 - 129 *Ruiying Li*, *Beihang University, University of Arizona (China); Wei Xie, The University of Arizona (United States)* 

## 08D - System Safety and Risk Analysis

Infusing Reliability Techniques into Software Safety Analysis - 08D1 - 247 *Ying Shi*, NASA/GSFC (United States)

SIL Requirements in Deepwater Drilling - Where Safety Meets Reliabilit - 08D2 - 202 *John Holmes*, *General Electric (United States)* 

Comparative Analysis of Static & Dynamic Probabilistic Risk Assessment - 08D3 - 207 *Christopher Mattenberger*, *Science and Technology Corp.* (*United States*)

Safety Driven Optimization Approach for Automotive Systems - 08D4 - 196

Mohamed Slim Dhouibi, VALEO - LARIS (France); Laurent Saintis, LARIS - ISTIA - Université
d'Angers (France); Mihaela Barreau, ISTIA (France); Jean-Marc Perquis, VALEO (France)

#### 08E - Accelerated Degradation and Life Testing

A Degradation Evaluation Method Based on Data from Multiple Conditions - 08E1 - 5 **Lizhi Wang**, Beihang University (China); Xiaohong Wang, Beihang University (China); Tianji Zou, School of Reliability and Systems Engineering, Beihang University (China); Han Xu, (China)

ESS/HASS Effectiveness Model for Yield and Screen Profile Optimization - 08E2 - 22 *Louis Gullo*, *Raytheon (United States)* 

Accelerated Degradation Testing of Coating of PCB under Humid Heat Environment - 08E3 - 162

**Xiaoming Ren**, Beihang University (China); Xiaohui Wang, Beihang University (China); Run Zhu, Beihang University (China)

HALTs from Hell; Lessons Learned - 08E4 - 84 James McLinn, Ops A La Carte (United States)

#### 09C - Accelerated Life Testing Applications

Influence of Tested Samples on Acceleration Factors Variation - 09C1 - 68

Frank Jakob, University of Stuttgart, Institute of Machine Components (Germany); Jochen Juskowiak, University of Stuttgart, Institute of Machine Components (Germany); Bernd Bertsche, University of Stuttgart, Institute of Machine Components (Germany)

Employing DOE to Optimize the Accelerated LifeTest Plan for TDDB - 09C2 - 73 Lingxiao Cheng, SMIC (China); Siyuan Frank Yang, SMIC (China); Wei-Ting Kary Chien, SMIC (China); Xiaofeng Xu, (United States)

Agitation System Accelerated Life Testing - 09C3 - 140 **Kummar Belanke**, iGATE Global Solutions Ltd. (India); Mukund Bagal, iGATE Global Solutions Ltd. (India); Sidharth Singh, iGATE Global Solutions Ltd. (India)

Flash-PLD Data Retention Times and Test Methods - 09C4 - 260

Gary Warren, SAIC (United States); Michael Demmick, (United States); Russell Warren, SAIC (United States)

# 09D - Reliability Modeling Techniques II

Reliability Analysis of a Hybrid Car Drive System with ECSPN - 09D1 - 91 **Timo Rieker**, University of Stuttgart, Institute of Machine Components (Germany); Peter Zeiler, University of Stuttgart, Institute of Machine Components (Germany); Bernd Bertsche, University of Stuttgart, Institute of Machine Components (Germany)

Probabilistic Competing Failure Analysis in Body Sensor Networks - 09D2 - 51

Yujie Wang, UMass Dartmouth (United States); Liudong Xing, UMass Dartmouth (United States); Honggang Wang, UMass Dartmouth (United States); Gregory Levitin, The Israel Electric Corporation Ltd. (Israel)

Bayesian Network for Reliability Prediction in Functional Design Stage - 09D3 - 203

Petek Yontay, Arizona State University (United States); Luis Mejia, Arizona State University (United States); Rong Pan, Ariozna State University (United States)

Reliability modeling of hydrogen fuel cells using Petri-Net simulation - 09D4 - 44

Michael Whiteley, Loughborough University (United Kingdom); Ashley Fly, Loughborough

University (United Kingdom); Johanna Leigh, Loughborough University (United Kingdom); Lisa

Jackson, Loughborough University (United Kingdom); Sarah Dunnett, Loughborough University

(United Kingdom)

#### 09E - Statistical Methods for R&M

A Bayesian Approach for Complex System Utilizing Imperfect Information - 09E1 - 223 Lechang Yang, Science and Technology on Reliability and Environment Engineering Laboratory (China); Pidong Wang, (China); Jianguo Zhang, Science and Technology on Reliability and Environment Engineering Laboratory (China); Yue Lu, Mr. (China)

Statistical Analysis of Accelerated life Testing under Weibull Distribution Based on Fuzzy Theory - 09E2 - 135

Han Xu, (China); Xiaoyang Li, (China); Le Liu, Science & Technology on Reliability & Environmental Engineering Laboratory, School of Reliability and Systems Engineering, Beihang University (China)

Acceleration Methods for Monte Carlo Simulation of Rare Events - 09E3 - 168

Maider Estecahandy, UPPA-TOTAL (France); Laurent Bordes, UPPA, LMAP (France);

Stéphane Collas, TOTAL S.A. (France); Christian Paroissin, UPPA, LMAP (France)

Warranty Forecasting of Electronic Boards using Short-term Field Data - 09E4 - 178 Mustafa Altun, Istanbul Technical University (Turkey); Salih Cömert, Istanbul Technical University (Turkey); Mustafa Nadar, Istanbul Technical University (Turkey); Ertunc Erturk, (Turkey)

# 11D - Strategies for Risk Avoidance Using FMEA

Capture All Critical Failure Modes into FMEA in Half the Time - 11D1 - 263 Howard C Cooper, General Dynamics - Land Systems Reliability (United States)

Risk Evaluation of STS Transfer Operations by Applying PFMEA and FIS - 11D2 - 280 *Dimitrios Stavrou*, NTUA (Greece); Nikolaos Ventikos, NTUA (Greece)

Electric Field Mapping Inside Metallized Film Capacitors - 11D3 - 299 **Dennis Nielsen**, Aalborg University (Denmark); Vladimir Popok, Aalborg University (Denmark); Kjeld Pedersen, (Denmark)

A Failure Mode Avoidance Approach to Reliability - 11D4 - 106

Anamika Saxena, University of Warwick (United Kingdom); Jeff Jones, (United Kingdom); Tim Davis, (United Kingdom)

#### 11E - Physical Failure Modeling & Applications II

Practical Applications of Semiconductor Reliability Modeling - 11E1 - 33

Lori Bechtold, Boeing (United States); Bahig Tawfellos, Honeywell Aerospace (United States);

David Sunderland, Boeing (United States); Florian Moliere, Airbus Group (France)

A Unifed Model Approach for Solder Joint Life Prediction - 11E2 - 66

Gurmukh Advani, North Dakota State University (United States); Om Prakash Yadav, North Dakota State University (United States)

Rocket Engine Failure Propagation Using Self-evolving Scenarios - 11E3 - 234 **Donovan Mathias**, NASA (United States); Samira Motiwala, NASA Ames Research Center (United States)

Electro-Thermal Modeling of IGBT with Experimental Validation - 11E4 - 291 Rui Wu, Aalborg university (Denmark); Francesco Iannuzzo, University of Cassino and southern Lazio (Italy); Huai Wang, (Denmark); Frede Blaabjerg, (Denmark)

#### 12C - R&M Applications in Manufacturing

Mechanical Reliability of a 126kV Single-break Vacuum Circuit Breaker - 12C1 - 90 Xiaofei Yao, Department of Electrical Engineering, Xi'an Jiaotong University (China); Zhiyuan Liu, Xi'an Jiaotong University (China); Yingsan Geng, Xi'an Jiaotong University (China); Jianhua Wang, Xi'an Jiaotong University (China)

Board Level Reliability Enhancements for Wafer Level Package - 12C2 - 122 John Qiao, Semiconductor Manufacturing International (Shanghai) Corp. (China); Wenwen He, Semiconductor Manufacturing International (Shanghai) Corp. (China); Kelly Yang, Semiconductor Manufacturing International (Shanghai) Corp. (China); Wei-Ting Chien, SMIC, Shanghai, China (China)

On Application of an Imperfect Repair Model in Maintenance Scheduling - 12C3 - 165 **Dinh Tuan Nguyen**, University of Technology of Troyes (France); Mitra Fouladirad, University of technology of Troyes (France); Yann Dijoux, University of Technology of Troyes (France)

Cost Effectiveness of Condition Based Maintenance in Manufacturing - 12C4 - 136 Ali Rastegari, Volvo GTO (Sweden); Marcus Bengtsson, Mälardalen University (Sweden)

## 12D - Risk Informed Decision Making

Modeling of Function Failure Propagation Across Uncoupled Systems - 12D1 - 180 Bryan O'Halloran, Raytheon Missile Systems (United States); Nikolaos Papakonstantinou, Aalto University (Finland); Douglas Van Bossuyt, Colorado School of Mines (United States)

Quantitative Mission Risk Assessment for Space Missions - 12D2 - 27 Andrew Hsu, The Aerospace Corporation (United States)

A Quantitative Model of Equipment Development Quality Risk Conduction - 12D3 - 154 Shaoqi Zhou, Beihang University (China); Wenbing Chang, Beihang University (China); Sheng-han Zhou, Beihang University (China); Wei Liu, Beihang University (China)

Reliability Growth Planning Curves Based on Multiple Phase Projections - 12D4 - 224 *Larry Crow, Crow Reliability Resources, Inc. (United States)* 

#### 12E - Prognostics and Health Management II

Modelling System Based on Fuzzy Dynamic Bayesian Network for Fault Dia - 12E1 - 88 *Jiao Li*, *Beihang University (China); Xiaogang Li*, *University of Beihang (China)* 

A Dual-parameter Optimization KPCA Method for Process Fault Diagnosis - 12E2 - 251 Jiang Hongquan, (China); Xu Gao, (China); Zhiyong Gao, (China); Yunlong Li, State Key Laboratory for Manufacturing Systems Engineering, Xi'an Jiaotong University (China)

Multiple Failure Modes Prognostics Using Logical Analysis of Data - 12E3 - 45
Ahmed Ragab, École Polytechnique of Montreal (Canada); Soumaya Yacout, École
Polytechnique of Montreal (Canada); Mohamed-Salah Ouali, École Polytechnique of Montreal
(Canada); Hany Osman, École Polytechnique of Montreal (Canada)

Computational Algorithm for Hybrid DBN in On-line SHM Applications - 12E4 - 72 *Chonlagarn Iamsumang*, *University of Maryland (United States)*; *Ali Mosleh*, *University of Maryland (United States)*; *Mohammad Modarres*, *University of Maryland (United States)* 

# 13C - Business Intelligence in Reliability

Leveraging Big Data to Improve Reliability & Maintainability - 13C1 - 163 Jun Li, NetApp Inc. (United States); Brad Reger, (United States); Steve Miller, (United States)

Design Integration of Hosted Payloads - Do No Harm Analysis - 13C2 - 60

Jack Kawamoto, The Aerospace Corporation (United States); Kenneth Dodson, SSL (United States); Steven Kuritz, Northrop Grumman Corporation (United States)

Aridity as a Factor in Estimating the Lifespan of Electronic Systems - 13C3 - 276

Abdullah Iliyasu, Tokyo Institute of Technology (Japan); **Khaled Abuhasel**, Salman Bin

Abdulaziz University (Saudi Arabia); Mohamed A. Al-Qodah, Salman Bin Abdulaziz University
(Saudi Arabia); Ismail Arafat, Salman Bin Abdulaziz University (Saudi Arabia)

Thermodynamic Damage Measurements of an Operating System - 13C4 - 305 *Alec Feinberg*, *DfRSoft* (*United States*)

# 13D - Network Modeling and Analysis

An Improved d-MP Search Algorithm for Mulit-State Networks - 13D1 - 63 **Guanghan Bai**, university of alberta (Canada); Ming Zuo, University of Alberta (Canada); Zhigang Tian, University of Alberta (Canada)

Reliability Analysis of Underwater Sensor Network Packet Transmission - 13D2 - 184 Lance Fiondella, University of Massachusetts (United States); Swapna Gokhale, University of Connecticut (United States); Jun-Hong Cui, University of Connecticut (United States)

An Application Oriented Evaluation Method for Network Performance Reliability - 13D3 - 158 **Yue Zhang**, Beihang University (China); Ning Huang, (China); Weiqiang Wu, Beihang University (China)

A New Model of Network Cascading Failures with Dependency Nodes - 13D4 - 133 **Jian Zhou**, Beihang University (China); Ning Huang, (China); Xiaolei Sun, Beihang University (China); Kunlong Wang, (China); HongQi Yang, Beihang University (China)

#### 14C - R&M Applications in Service

Maintenance Resource Planning for Utility Poles in a Power Network - 02E4 - 48

Maliheh Aramon Bajestani, University of Toronto (Canada); Neil Montgomery, University of Toronto (Canada); Dragan Banjevic, University of Toronto (Canada); Andrew Jardine, University of Toronto (Canada)

Leveraging Unstructured data to Detect Emerging Reliability Issues - 14C1 - 161 **Deovrat Kakde**, SAS Institute (United States); Arin Chaudhuri, SAS Institute (United States) Simulation for Psychological Factors-considered Repair based on Swarm - 14C2 - 141 Xuhua Liu, Beihang University (China); Lin Ma, Beihang University (China); Longfei Yue, Beihang University (China); Haoran Deng, Beihang University (China)

Insights into Process Reliability through Simulation - 14C4 - 172 Venkatesh Agaram, PTC, Inc. USA (United States); Julian Venegas, PTC, Inc. (United States)

## 14D - R&M Management Under New Challenges II

A New Reliability Growth Model with Dual-Time Domain - A Hard Disk Drive Perspective - 05E3 - 110

Feng-Bin Sun, HGST, A Western Digital Company (United States)

A Vision for Spaceflight Reliability: NASA's Objectives Based Strategy - 14D2 - 18 Frank Groen, NASA HQ (United States); John Evans, NASA HQ (United States); Anthony Hall, Information Systems Laboratories (United States)

The Electronic Maintenance Situational Awareness Interface - 14D3 - 281

Allan Cesar Moreira de Oliveira, Federal University of Sao Carlos (Brazil); Clayton

VanVolkenburg, University of Toronto (Canada); Andrew Jardine, University of Toronto

(Canada); Regina Borges de Araujo, Federal University of Sao Carlos (Brazil)

A Petri Net Model for Electrical Power Systems Operating Procedures - 14D4 - 109 Giovanni Vescio, Technip (Italy); Paolo Riccobon, Technip (Italy); Umberto Grasselli, Università Sapienza Rome - DIAEE (Italy); Francesco De Angelis, University of Rome La Sapienza DIAEE (Italy)